

TECHNICAL SPEC FOR Overlay measurement system

System Model:

Soluris IVS 130

Wafer size: 6 and 8 inch

SECS/GEM:Yes

SMIF: no

Auto template illumination: yes

FSF and edge contrast focus systems: yes

Handler: 6/8 inch robot Cybeq

Pre-aligner, yes

Cassette stations: 3

Asyst SMIF indexers: no SMIF

Vintage: 2003

Missing parts: wafer robot is defective

Defected parts: wafer robot